

Accelerating the Parametric Identification of the Monod System Using Explicit and Implicit Schemas

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Abstract – current study is a research of different schemas identifying the Monod nonlinear stiff ODE. The schemas provide better performance and accuracy in comparison with the classic implicit ODE solvers.

Keywords – parametric identification, Monod system, stiff ODE, explicit schema, implicit schema.

I. INTRODUCTION

The Monod system is widely used as a model of fermenting processes. Refining the speed and accuracy of parametric identification of such a model is of much interest in chemical and technological research.

Current study aims to discover the abilities to accelerate the identification speed using a limited explicit schema and compares these results with those obtained using the explicit-implicit schema of [1].

II. STIFFNESS OF THE MONOD MODEL

Isothermal fermentation processes can be modeled using a Cauchy problem for the autonomous Monod ODE system. The numeric approximation of the problem solution can be obtained using the Euler explicit schema

$$X_{k+1} = (1 + hI_{1,k})X_k, \quad S_{k+1} = (1 + hI_{2,k})S_k, \quad (1)$$

$$P_{k+1} = P_k + hA_7A_3 \frac{S_k X_k}{A_4 + S_k} \left(1 - \frac{2P_k}{S_0}\right), \quad (2)$$

with initial conditions $X_0 > 0$, $S_0 > 0$, $P_0 = 0$, where X_k is the biomass concentration at k^{th} time discrete, S_k is the substrate concentration, P_k the is product (ethanol) concentration, $I_{1,k}$ and $I_{2,k}$ are computed as

$$I_{1,k} = A_1 \frac{S_k}{A_5 + P_k} - A_2, \quad I_{2,k} = -\frac{A_3 X_k}{A_4 + S_k} \quad (3)$$

Equations (1) are conditionally stable and don't lose their physical sense ($X_k \geq 0$, $S_k \geq 0$, $k = 0, 1, 2, \dots$) when the conditions

$$-1 \leq hI_{1,k}, \quad -1 \leq hI_{2,k} \quad (4)$$

are satisfied. Eq. (2) is always stable, because its right side is always greater than zero.

The large absolute value of $I_{1,k}$ or $I_{2,k}$ require reduced value of step h in order to satisfy (4). Small values of h leads to increased computation time in schema (1)–(3), because every next $k+1^{\text{th}}$ time discrete is increased by $h = t_{k+1} - t_k$. Moreover, in the case when one I is drastically greater than the

opposite one, i.e. $|I_{1,k}| \gg \gg |I_{2,k}|$ or $|I_{2,k}| \gg \gg |I_{1,k}|$, the product $hI_{2,k}$ or $hI_{1,k}$ can lead to a machine zero, refusing the computation accuracy. Such a phenomena is known as the stiffness of ODE system.

The largest stiffness is observed at the end of the process, when $X_k \rightarrow 0$, $S_k \rightarrow 0$ and $I_{1,k} \rightarrow -A_2$, $I_{2,k} \rightarrow 0$ leading to $|I_{1,k}| \gg \gg |I_{2,k}|$.

III. THE EXPLICIT-IMPLICIT AND LIMITED SCHEMAS

In order to attack this problem, a new explicit-implicit method is developed.

Theoretical research, conducted in [1] leads to the following equation for boundary substrate value

$$S_{bound} = -h^* S'_{real,m}, \quad (5)$$

where $S'_{real,m}$ is a finite difference approximation of substrate derivative at time m , when a half of substrate was consumed, i.e. $S_{real,m} \approx 0.5S_0$; h^* is maximal step value.

The eq. (5) defines time area, where an explicit schema is still applicable, i.e. all $k=0, 1, 2, \dots$ for which $S_k > S_{bound}$.

The limited schema is based on the observation that $S_k \rightarrow 0$ and $P_k \rightarrow 0.5S_0$ when $k \rightarrow \infty$. So the model (1)–(2) can be reduced to

$$X_k = X_q \exp[-A_2(t_k - t_q)], \quad S_k = 0, \quad P_k = P_q, \quad (6)$$

starting from some q^{th} time node ($k = q, q+1, \dots$), where $S_q \leq S_{lim}$. System is solved using the explicit (1)–(2) schema for $0 \leq k \leq q$ and using (6) for the rest $k > q$.

IV. RESULTS AND CONCLUSION

The explicit-implicit scheme (5) reduces the duration of identification procedure up to 46%, and gets the identification error of 32% in relation to the classic implicit scheme [1].

The new result is the ability to reduce the duration of identification up to 29% using the limited schema (6) without enormous increases in identification errors, i.e. no more than 5% in relation to X_k , S_k and P_k maximal values.

REFERENCES

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